

## CT350 Comet C

Modular and very compact test system with  
High Pin Count Interface and integrated PC  
Relative small volume W x H x D [cm]: 55 x 67 x 60

### Function Test and In-circuit Test / MDA

- ICT test points: max. 2736
- CAD data import
- Automatic program generator
- Full graphic operator screen
- Powerful debugging tools
- Test coverage analysis
- Paperless repair station
- Logging and statistic functions
- High Pin Count-Interface
- Fast adapter exchange
- Handler and adapter controlling
- Innovative combinational test
- Mixed signal tests
- 300 MS/s digital, 1 GS/s analog
- Amplitude resolution 24 bit
- Current measurement resolution 1 pA
- Controlling power supplies up to 10 kW
- Fast pulse measurement procedures
- Interface Tester <=> PC: High Speed USB
- Short test times, high throughput
- Modular system
- Concurrent engineering
- Complete problem solutions
- Fast and reliable support
- Very good price-performance ratio



Vacuum  
compressed air

### High Pin Count Interface



Very fast adapter exchange